Appl No. 10/762,122 Amdt. dated Mar. 14, 2005

Reply to Office action of Dec. 13, 2004

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

- 1-15. (cancelled)
- 16. (currently amended) A method for forming a leadframe for use in the assembly of integrated circuit devices, comprising:

providing a base metal structure;

forming a nickel layer on the metal structure;

forming a <u>matte</u>, <u>coarse grain</u>, <u>tin</u> solder layer on the nickel layer selectively, covering an area of said leadframe for attaching a integrated circuit chip; and forming a palladium or silver layer selectively, covering an area of said leadframe suitable for attaching a bonding wire.

- 17. (previously presented) The method in Claim 16 wherein the base metal structure includes copper, copper alloy, aluminum, iron-nickel alloy, or invar.
- 18. (canceled)
- 19 (currently amended) The method in Claim [18] <u>16</u> wherein said tin solder has a reflow temperature of 232 °C.
- 20. (currently amended) The method in Claim [18] 16 wherein the solder layer has a thickness in the range from about 4.0 to 6.0 μm.
- 21. (previously presented) The method in Claim 16 wherein said palladium or silver layer has a thickness in the range from about 20 to 60 nm.

Appl No. 10/762,122 Amdt. dated Mar. 14, 2005 Reply to Office action of Dec. 13, 2004

22. (currently amended) A method for forming a leadframe for use with integrated circuit chips comprising:

providing a base metal structure having a plated layer of nickel fully covering said base metal;

forming a layer of <u>matte</u>, <u>coarse grain</u>, pure tin on said nickel layer selectively, covering an area of said leadframe suitable for attaching a circuit chip; and forming a layer of palladium or silver on said nickel layer selectively, covering an area of said leadframe suitable for attaching a bonding wire.

Appl No. 10/762,122 Amdt. dated Mar. 14, 2005 Reply to Office action of Dec. 13, 2004

- 23. (currently amended) A method for forming a semiconductor device comprising: providing a leadframe including a chip-mount pad and a lead segment having a first end near said mount pad and a second end remote from said mount pad; forming a nickel layer over said leadframe; forming a layer of palladium on said nickel layer selectively, covering said first end of said lead segment; attaching an integrated circuit chip to said mount pad; and applying a layer of matte, coarse grain, pure tin solder selectively, covering said second end of said lead segment.
- 24. (previously presented) The method in Claim 23 further comprising bending the lead segment suitable for solder attachment.